HI2300

8-Bit, 18 MSPS, Video A/D Converter with 3.3V Power Supply Operation

August 1997

- Reference Voltage Self-Bias Circuit
 Input CMOS Compatible
- Three-State TTL Compatible Output
- Power Supply 3.3V Single
- Low Input Capacitance8pF
- Direct Replacement for Sony CXD2300

Applications

- · Portable Equipment
- · Hand-Held Instruments

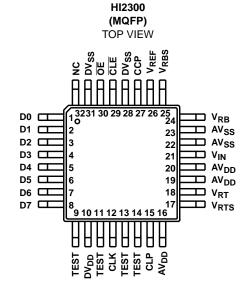
Description

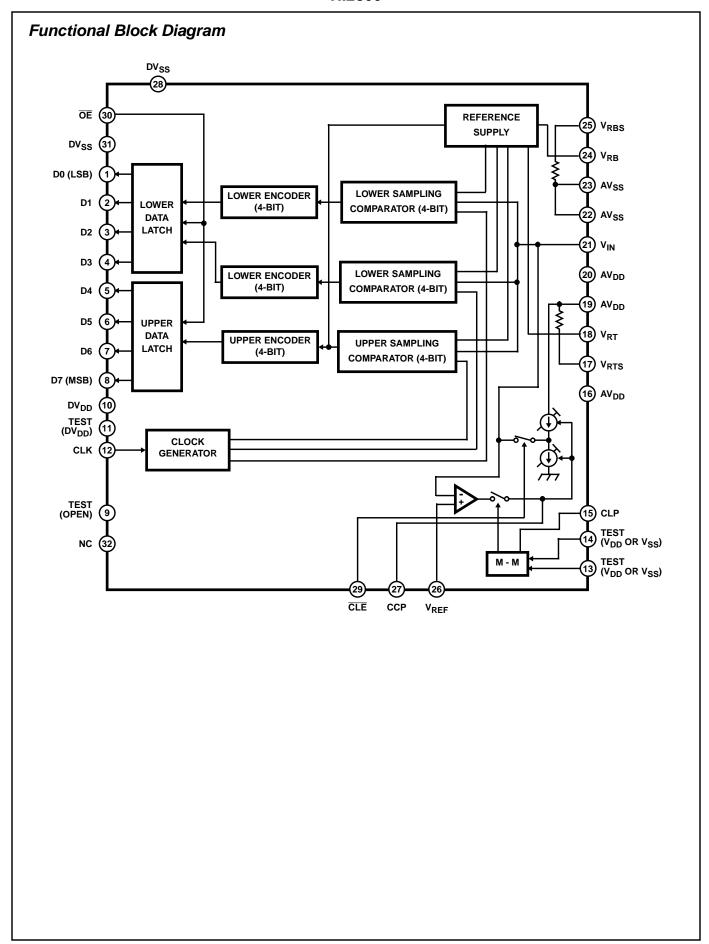
The HI2300 is an 8-bit, CMOS A/D converter for video with synchronizing clamp function and can operate on 3.3V power supply. The adoption of 2 step-parallel method achieves ultra-low power consumption and a maximum conversion speed of 18 MSPS.

Ordering Information

PART NUMBER	TEMP. RANGE (°C)	PACKAGE	PKG. NO.	
HI2300JCQ	-40 to 85	32 Ld MQFP	Q32.7x7-S	

Pinout





Pin Descriptions

PIN NUMBER	SYMBOL	EQUIVALENT CIRCUIT	DESCRIPTION				
1 to 8 D0 to D7			D0 (LSB) to D7 (MSB) Output.				
9	TEST	9 DV _{DD} DV _{SS}	Leave open during normal usage.				
10	DV _{DD}		Digital +3.3V.				
12	CLK	DV _{DD} DV _{SS}	Clock Input.				
11, 13, 14	TEST	DV _{DD} DV _{SS}	Fix Pin 11 to V _{DD} , Pins 13 and 14 to V _{DD} over V _{SS} during normal usage.				
15	CLP	(15) DV _{DD}	Inputs Clamp Pulse to Pin 15 (CLP). Clamp the signal voltage during Low interval.				
16, 19, 20	AV _{DD}		Analog +3.3V				
17	V _{RTS}	AV _{DD}	Generates approximately +1.8V when shorted with V _{RT} .				
18	V _{RT}	o AV _{DD}	Reference Voltage (Top).				
24	V _{RB}	18 AV _{SS}	Reference Voltage (Bottom).				

Pin Descriptions (Continued)

PIN NUMBER	SYMBOL	EQUIVALENT CIRCUIT	Analog Input.				
21	V _{IN}	21 AV _{DD}					
25	V _{BRS}	AV _{SS}	Generates approximately +0.4V when shorte with $\ensuremath{V_{RB}}.$				
26	V _{REF}	AV _{DD} AV _{SS}	Clamp Reference Voltage Input. Clamps s that the reference voltage and the input signs during clamp interval are equal.				
27	CCP	AV _{DD} AV _{SS}	Integrates the clamp control voltage. The relationship between the changes in CC voltage and in V _{IN} voltage is positive phase.				
28, 31	DV _{SS}		Digital Ground.				
29	CLE	29 CLAMP PULSE	The clamp function is enabled when \$\overline{CLE}\$ = Low. The clamp function is set to off and the converter functions as a normal A/D converted when \$\overline{CLE}\$ = High. The clamp pulse can be measured be connecting \$\overline{CLE}\$ to \$DV_{DD}\$ through several-hundred-ohm resistor.				
30	ŌĒ	30 DV _{DD}	Data is output when \overline{OE} = Low. Pins D0 to D are at high impedance when \overline{OE} = High.				
		6 DV _{SS}					

HI2300

Absolute Maximum Ratings T_A = 25°C **Thermal Information** Supply Voltage (V_{DD})......7V Thermal Resistance (Typical, Note 1) θ_{JA} (°C/W) Reference Voltage (V_{RT}, V_{RB}).....V_{DD} +0.5V to V_{SS} - 0.5V Maximum Junction Temperature (Plastic Package) 150°C Input Voltage, Digital (V $_{IH}$, V $_{IL}$)V $_{DD}$ +0.5V to V $_{SS}$ - 0.5V Output Voltage, Digital (V $_{OH}$, V $_{OL}$)V $_{DD}$ +0.5V to V $_{SS}$ - 0.5V Maximum Storage Temperature Range-65°C to 150°C Maximum Lead Temperature (Soldering 10s).....300°C (MQFP - Lead Tips Only) **Recommended Operating Conditions** Temperature Range (t_{OPR}) -40°C to 85°C Analog Input (ADIN) V_{RT} to V_{RB} Supply Voltage (IDV_{SS} - AV_{SS}I). 0 to 100mV Clock Pulse width (t_{PW1}) 27ns (Min) Power Supply (DV_{DD}, DV_{SS})(AV_{DD}, AV_{SS}). 3.14V to 4.0V (V_{RT}).....1.8V

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTE:

1. θ_{JA} is measured with the component mounted on an evaluation PC board in free air.

Electrical Specifications When using a single power supply; $f_C = 18$ MSPS, $V_{DD} = 3.3V$, $V_{RB} = 0V$, $V_{RT} = 1.5V$, $T_A = 25^{\circ}C$

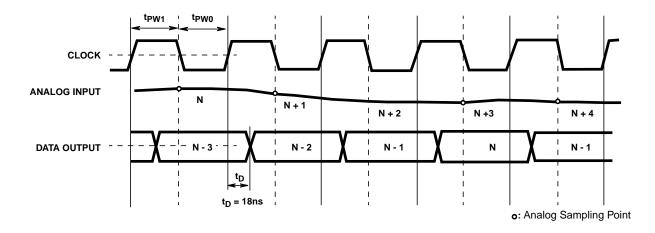
PARAMETER	SYMBOL	TEST CONDITIONS		MIN	TYP	MAX	UNITS
Maximum Conversion Rate	f _C Max	V _{IN} = 0 to 1.5V		18	32	-	MSPS
Minimum Conversion Rate	f _C Min	f _{IN} = 1kHz Ramp	=	32	0.5	MSPS	
Supply Current	I _{DD}	$f_C = 18 \text{ MSPS}, N^T$	f _C = 18 MSPS, NTSC Ramp Wave Input			10	mA
Reference Pin Current	I _{REF}			3.3	4.6	6.6	mA
Analog Input Band Width	BW	$V_{IN} = 1.4V_{P-P}, 1$	7.9MHz	-	9	-	dB
Analog Input Capacitance	C _{IN}	$V_{IN} = 0.75V + 0.0$	07 V _{RMS}	-	8	-	pF
Reference Resistance (V _{RT} to V _{RB})	R _{REF}			230	330	440	Ω
Self Bias I	V _{RB1}	Shorts V _{RB} and	V _{RBS}	0.33	0.36	0.39	V
	V _{RT1} - V _{RB1}	Shorts V _{RT} and V	V _{RTS}	1.30	1.39	1.48	V
Offset Voltage	E _{OT}			-45	-25	-5	mV
	E _{OB}			40	60	80	mV
Digital Input Voltage	V _{IH}			2.5	-	-	V
	V _{IL}			-	-	0.5	V
Digital Input Current	I _{IH}	V _{DD} = Max	$V_{IH} = V_{DD}$	-	-	5	μΑ
	I _{IL}		$V_{IL} = 0V$	-	-	-	μΑ
Digital Output Current	ГОН	OE = V _{SS}	$V_{OH} = V_{DD} - 0.5V$	-1.0	-	-	mA
	I _{OL}	$V_{DD} = Min$	V _{OL} = 0.4V	3.3	-	-	mA
Digital Output Current	lozh	OE = V _{DD}	$V_{OH} = V_{DD}$	-	-	16	μΑ
	I _{OZL}	V _{DD} = Max	V _{OL} = 0V	-	-	16	μΑ
Output Data Delay	t _{DL}	With TTL 1 Gate and 10pF Load		8	18	30	ns
Three-State Output Enable Time	t _{PZH}	$R_L = 1k\Omega$, $C_L = 20pF$, $\overline{OE} = 3V \rightarrow 0V$					
	t _{PZL}						
Three-State Output Disable Time	t _{PHZ}	$R_L = 1k\Omega$, $C_L = 2$					
	t _{PLZ}						
Integral Nonlinearity Error	EL	$f_C = 18 \text{ MSPS}$ $V_{IN} = 0 \text{ to } 1.5 \text{V}$	-	+0.5	±1.3	LSB	
Differential Nonlinearity Error	E _D	f _C = 18 MSPS V _{IN} = 0 to 1.5V		-	±0.3	±0.5	LSB
Aperture Jitter	t _{AJ}			-	30	-	ps
Sampling Delay	t _{SD}			-	4	-	ns
Clamp Offset Voltage	E _{OC}	V _{IN} = DC	V _{REF} = 0.5V	-20	0	+20	mV
		PWS = 3μs	V _{REF} = 1.5V	-30	-10	+10	mV
Clamp Pulse Delay	tCPD			-	25	-	ns

Digital Output

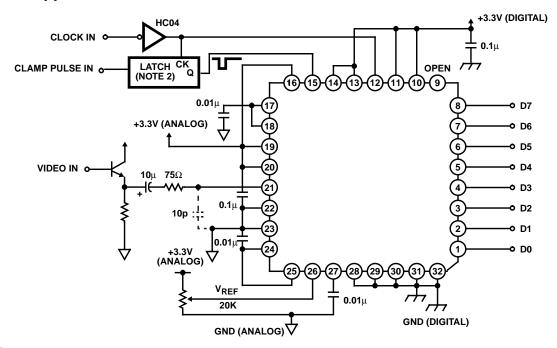
The following table shows the relationship between analog input voltage and digital output code.

		DIGITAL OUTPUT CODE							
INPUT SIGNAL VOLTAGE	STEP	M	SB					LS	SG
V _{RT}	0	1	1	1	1	1	1	1	1
•	•				•	•			
•	•				•	•			
•	•					•			
•	127	1	0	0	0	0	0	0	0
	128	0	1	1	1	1	1	1	1
	•					•			
	•					•			
	•								
V _{RB}	255	0	0	0	0	0	0	0	0

Timing Chart



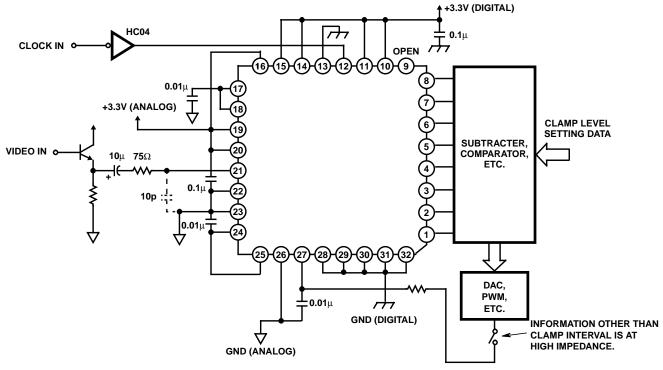
Typical Application Circuits



NOTE:

1. The clamp pulse is latched by the sampling clock of ADC, but that is not necessary for basic clamp operaiotn. However, slight small beat may be generated as Vertical sag according to the relationship between the sampling frequency and the clamp pulse frequency. At such time, the latch circuit is efective in this case.

FIGURE 1. WHEN CLAMP IS USED (SELF BIAS)



NOTES:

- 2. The relationship between the changes in CCP voltage (Pin 27) and in V_{IN} voltage is positive phase.
- 3. $\Delta V_{IN}/\Delta V_{CCP} = 3.0$ (f_S = 20 MSPS).

FIGURE 2. DIGITAL CLAMP (SELF BIAS)

Typical Application Circuits (Continued)

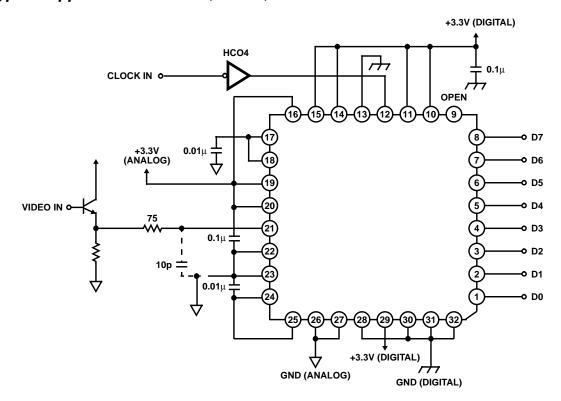


FIGURE 3. WHEN CLAMP IS NOT USED (SELF BIAS)

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